May 2001

ТМ

FQB20N06L / FQI20N06L

SEMICONDUCTOR®

FQB20N06L / FQI20N06L **60V LOGIC N-Channel MOSFET**

General Description

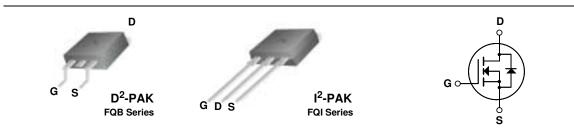
FAIRCHILD

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as automotive, DC/ DC converters, and high efficiency switching for power management in portable and battery operated products.

Features

- + 21A, 60V, $R_{DS(on)}$ = 0.055 Ω @V_{GS} = 10 V + Low gate charge (typical 9.5 nC)
- · Low Crss (typical 35 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating



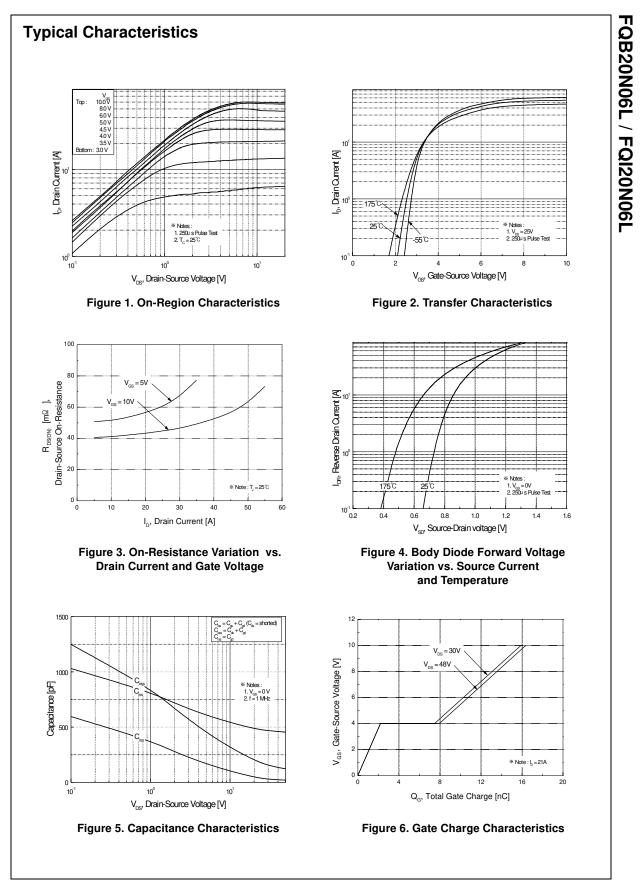
Absolute Maximum Ratings T_c = 25°C unless otherwise noted

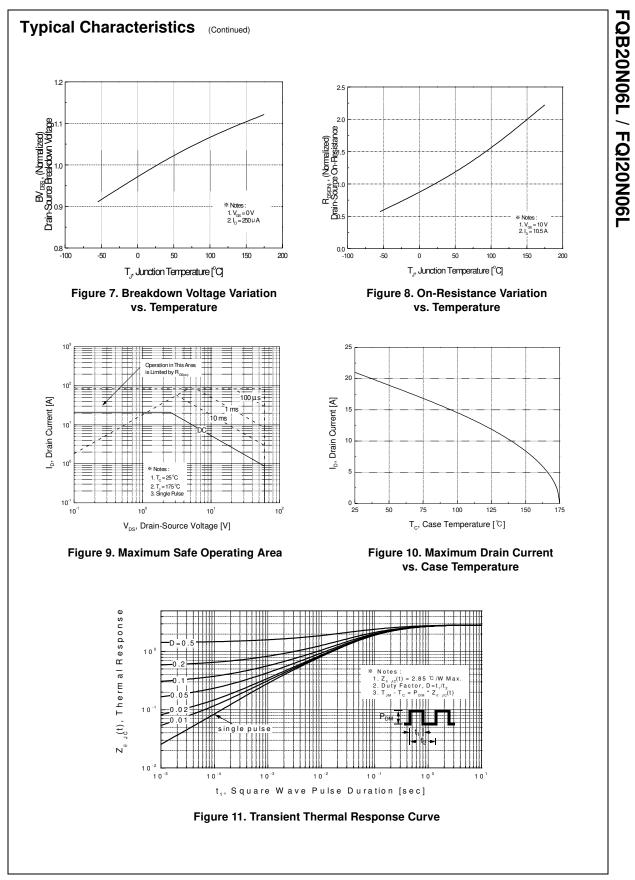
Symbol	Parameter		FQB20N06L / FQI20N06L	Units
V _{DSS}	Drain-Source Voltage		60	V
ID	Drain Current - Continuous (T _C = 25°	C)	21	А
	- Continuous (T _C = 100	°C)	14.7	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	84	Α
V _{GSS}	Gate-Source Voltage		± 20	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	170	mJ
I _{AR}	Avalanche Current	(Note 1)	21	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	5.3	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
PD	Power Dissipation $(T_A = 25^{\circ}C)^{*}$		3.75	W
	Power Dissipation $(T_C = 25^{\circ}C)$		53	W
	- Derate above 25°C		0.35	W/°C
T _J , T _{STG}	Operating and Storage Temperature Ran	ge	-55 to +175	°C
TL	Maximum lead temperature for soldering 1/8" from case for 5 seconds	purposes,	300	°C

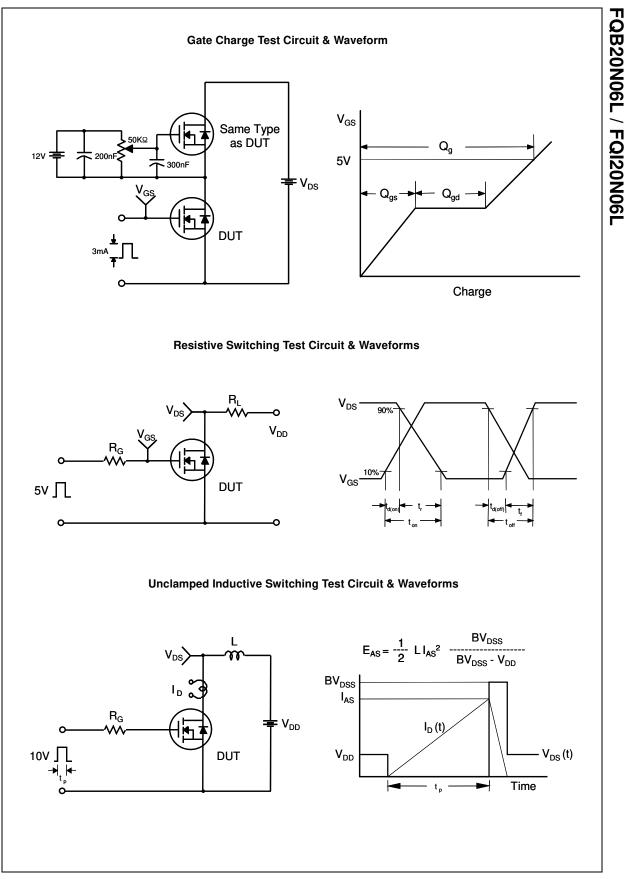
Thermal Characteristics

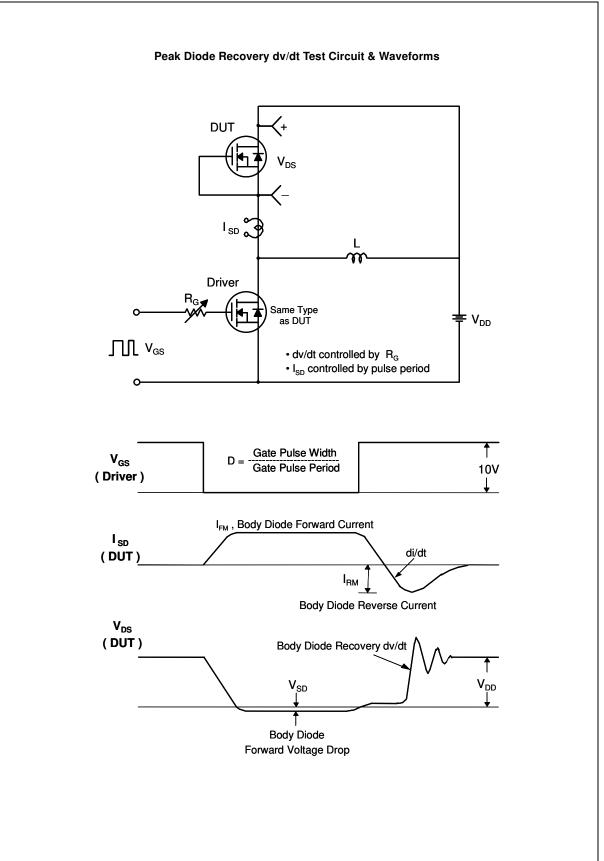
Symbol	Parameter	Тур	Max	Units
R _{θJC}	Thermal Resistance, Junction-to-Case		2.85	°C/W
R _{0JA}	Thermal Resistance, Junction-to-Ambient *		40	°C/W
R _{θJA}	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

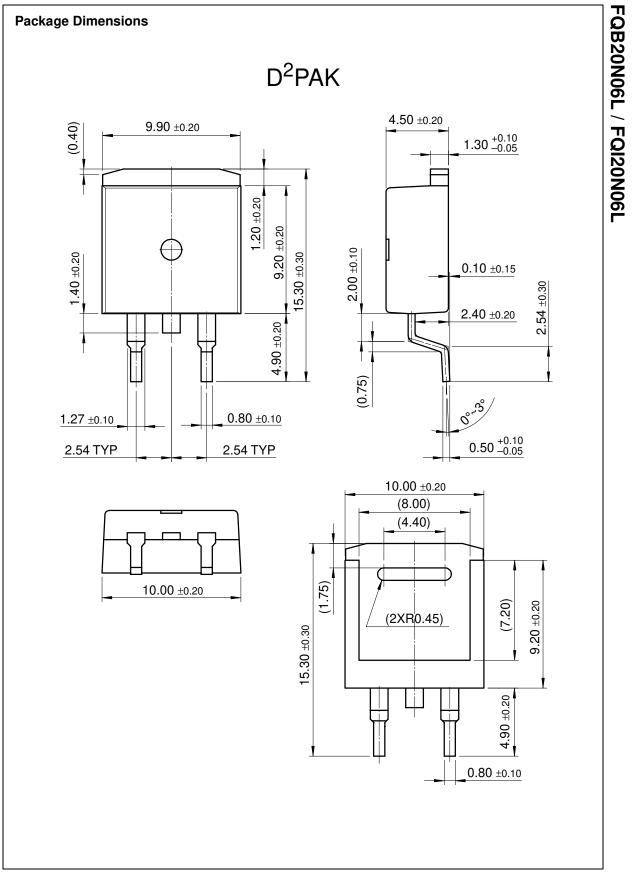
	Test Conditions		Тур	Max	Units
racteristics					
Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	60			V
Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25°C		0.06		V/°C
Zara Cata Valtaga Drain Current	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
Zero Gate voltage Drain Current	$V_{DS} = 48 \text{ V}, \text{ T}_{C} = 150^{\circ}\text{C}$			10	μA
Gate-Body Leakage Current, Forward	V_{GS} = 20 V, V_{DS} = 0 V			100	nA
Gate-Body Leakage Current, Reverse	$V_{GS} = -20 V, V_{DS} = 0 V$			-100	nA
racteristics					
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0		2.5	V
Static Drain-Source	V _{GS} = 10 V, I _D = 10.5 A		0.042	0.055	0
On-Resistance	$V_{GS} = 5 V, I_{D} = 10.5 A$		0.055	0.07	Ω
Forward Transconductance	$V_{DS} = 25 \text{ V}, I_D = 10.5 \text{ A}$ (Note 4)		11		S
c Characteristics					
	$V_{} = 25 V V_{} = 0 V$		480	630	pF
			175	230	pF
			35	45	pF
ng Characteristics		1	10		
Turn-On Delay Time			10	30	ns
Turn-On Delay Time Turn-On Rise Time	$V_{DD} = 30 \text{ V}, \text{ I}_{D} = 10.5 \text{ A},$		10 165	30 340	ns ns
	$V_{DD} = 30 \text{ V}, \text{ I}_{D} = 10.5 \text{ A},$ $R_{G} = 25 \Omega$				
Turn-On Rise Time			165	340	ns
Turn-On Rise Time Turn-Off Delay Time	$R_G = 25 \ \Omega$ (Note 4, 5)		165 35	340 80	ns ns
Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time	$R_G = 25 \ \Omega$ (Note 4, 5) V _{DS} = 48 V, I _D = 21 A,		165 35 70	340 80 150	ns ns ns
Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge	$R_G = 25 \ \Omega$ (Note 4, 5)	 	165 35 70 9.5	340 80 150 13	ns ns ns nC
Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge Cource Diode Characteristics ar	$R_{G} = 25 \ \Omega$ $(Note 4, 5)$ $V_{DS} = 48 \ V, \ I_{D} = 21 \ A,$ $V_{GS} = 5 \ V$ $(Note 4, 5)$ $(Note 4, 5)$	 	165 35 70 9.5 2.5	340 80 150 13 	ns ns nC nC
Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge Fource Diode Characteristics ar Maximum Continuous Drain-Source Dio	$R_{G} = 25 \ \Omega$ $(Note 4, 5)$ $V_{DS} = 48 \ V, I_{D} = 21 \ A,$ $V_{GS} = 5 \ V$ $(Note 4, 5)$	 	165 35 70 9.5 2.5	340 80 150 13 21	ns ns nC nC nC
Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge Source Diode Characteristics ar Maximum Continuous Drain-Source Diode F	$R_{G} = 25 \ \Omega$ $(Note 4, 5)$ $V_{DS} = 48 \ V, \ I_{D} = 21 \ A,$ $V_{GS} = 5 \ V$ $(Note 4, 5)$ $Note 4, 5)$	 	165 35 70 9.5 2.5 5.5	340 80 150 13 	ns ns nC nC nC
Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge Fource Diode Characteristics ar Maximum Continuous Drain-Source Diode F Maximum Pulsed Drain-Source Diode F Drain-Source Diode Forward Voltage	$eq:rescaled_$	 	165 35 70 9.5 2.5 5.5	340 80 150 13 21	ns ns nC nC nC
Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge Source Diode Characteristics ar Maximum Continuous Drain-Source Diode F	$R_{G} = 25 \ \Omega$ $(Note 4, 5)$ $V_{DS} = 48 \ V, \ I_{D} = 21 \ A,$ $V_{GS} = 5 \ V$ $(Note 4, 5)$ $Note 4, 5)$	 	165 35 70 9.5 2.5 5.5	340 80 150 13 21 84	ns ns nC nC nC
	Gate-Body Leakage Current, Reverse racteristics Gate Threshold Voltage Static Drain-Source On-Resistance Forward Transconductance c Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance	Zero Gate Voltage Drain Current $V_{DS} = 48 \text{ V}, \text{ T}_{C} = 150^{\circ}\text{C}$ Gate-Body Leakage Current, Forward $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ racteristicsGate Threshold Voltage $V_{DS} = V_{GS}, \text{ I}_{D} = 250 \mu\text{A}$ Static Drain-Source $V_{GS} = 10 \text{ V}, \text{ I}_{D} = 10.5 \text{ A}$ On-Resistance $V_{DS} = 25 \text{ V}, \text{ I}_{D} = 10.5 \text{ A}$ Forward Transconductance $V_{DS} = 25 \text{ V}, \text{ I}_{D} = 10.5 \text{ A}$ Input Capacitance $V_{DS} = 25 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ f = 1.0 MHzf = 1.0 MHz	Zero Gate Voltage Drain Current $V_{DS} = 48 \text{ V}, T_C = 150^{\circ}\text{C}$ Gate-Body Leakage Current, Forward $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ racteristicsGate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \mu \text{A}$ 1.0Static Drain-Source $V_{GS} = 10 \text{ V}, I_D = 10.5 \text{ A}$ On-Resistance $V_{DS} = 25 \text{ V}, I_D = 10.5 \text{ A}$ Forward Transconductance $V_{DS} = 25 \text{ V}, I_D = 10.5 \text{ A}$ c CharacteristicsInput Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ Output Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ Reverse Transfer Capacitance	Zero Gate Voltage Drain Current $V_{DS} = 48 \text{ V}, T_C = 150^{\circ}\text{C}$ Gate-Body Leakage Current, Forward $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ racteristicsGate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \mu \text{A}$ 1.0Static Drain-Source $V_{GS} = 10 \text{ V}, I_D = 10.5 \text{ A}$ 0.042On-Resistance $V_{GS} = 5 \text{ V}, I_D = 10.5 \text{ A}$ 0.055Forward Transconductance $V_{DS} = 25 \text{ V}, I_D = 10.5 \text{ A}$ 11c CharacteristicsInput Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ 480Output Capacitance $f = 1.0 \text{ MHz}$ 175Reverse Transfer Capacitance35	Zero Gate Voltage Drain Current $V_{DS} = 48 \text{ V}, T_C = 150^{\circ}\text{C}$ 10 Gate-Body Leakage Current, Forward $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$ 100 Gate-Body Leakage Current, Reverse $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$ 100 Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ 100 racteristics Gate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \mu \text{ A}$ 1.0 2.5 Static Drain-Source $V_{GS} = 10 \text{ V}, I_D = 10.5 \text{ A}$ 0.042 0.055 On-Resistance $V_{GS} = 5 \text{ V}, I_D = 10.5 \text{ A}$ 11 Forward Transconductance $V_{DS} = 25 \text{ V}, I_D = 10.5 \text{ A}$ (Note 4) 11 Characteristics Input Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ 480 630 Output Capacitance $f = 1.0 \text{ MHz}$ 35 45

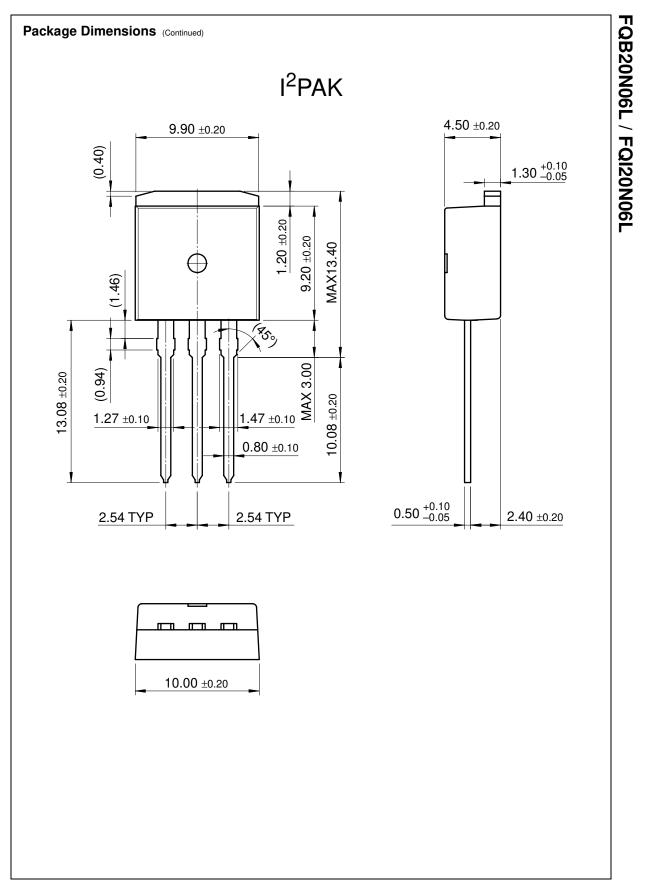












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Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as DC/DC converters, high efficiency switching for power management in portable and battery operated products.

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Features

- 21A, 60V, $R_{DS(on)} = 0.055\Omega @V_{GS} =$ 10 V
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Product status/pricing/packaging

Product	Product status	Pricing*	Package type	Leads	Packing method
FQI20N06LTU	Full Production	\$0.56	TO-262(I2PAK)	3	RAIL

* 1,000 piece Budgetary Pricing

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Models

Package & leads	Condition	Temperature range	Software version	Revision date
PSPICE				
TO-262(I2PAK)-3	Electrical/Thermal	-55°C to 175°C	9	Mar 25, 2000

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Product	Product status	Pricing*	Package type	Leads	Packing method
FQB20N06LTM	Full Production	\$0.56	TO-263(D2PAK)	2	TAPE REEL

* 1,000 piece Budgetary Pricing

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Models

Package & leads	Condition	Temperature range	Software version	Revision date
PSPICE				
TO-263(D2PAK)-2	Electrical/Thermal	-55°C to 175°C	9	Mar 25, 2000

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